

<b>Notice of References Cited</b>	Application/Control No. 10/755,666	Applicant(s)/Patent Under Reexamination VAN DER BIGGELAAR ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2003/0035090 A1	02-2003	Imai et al.	355/53
	C	US-			
	D	US-			
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	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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